

Optical Beam Profiler Based on Compressive Imaging

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Technology Summary

The Optical Beam Profiler based on Compressive Imaging makes use of compressive imaging methods to measure optical beam profiles. The device can be used as a replacement for traditional beam profiling tools, but has the advantage that its utility extends to domains not accessible to traditional techniques. In particular, the technique can be used for very low-intensity beams (down to a few photons) and for wavelengths for which it is difficult to fabricate many-pixel detector arrays.

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